

# **RoHS Recast Compliant**

# **USB Flash Drive**

Industrial UH110-UFD1 BiCS5 Product Specifications



August 6, 2024

Version 1.3



**Apacer Technology Inc.** 

1F, No.32, Zhongcheng Rd., Tucheng Dist., New Taipei City, Taiwan, R.O.C Tel: +886-2-2267-8000 Fax: +886-2-2267-2261

www.apacer.com

## **Specifications Overview:**

- USB 3.2 Gen1 Super Speed compatible, and backward compatible with USB 2.0 & USB 1.1 interfaces
  - USB 3.2 Gen1 max. transfer rate: 5 Gb/s
  - Backward compatible with 480Mb/s for USB 2.0 & 12 Mb/s for USB 1.1
- Capacity
  - 32, 64 GB
- Performance<sup>1</sup>
  - Sequential read: Up to 280 MB/sec
  - Sequential write: Up to 190 MB/sec
  - Random read (4K): Up to 3,200 IOPS
  - Random write (4K): Up to 1,500 IOPS
- Flash Management
  - Built-in hardware Low Density Parity-Check (LDPC) ECC
  - Global Wear Leveling
  - Flash bad-block management
  - Flash Translation Layer: Page Mapping
  - Power Failure Management
  - S.M.A.R.T.
  - SMART Read Refresh™
  - SLC-liteX
- NAND Flash Type: 3D TLC (BiCS5)
- MTBF: >3,000,000 hours
- Endurance (in drive writes per day: DWPD)
  - 32 GB: 21.7 DWPD64 GB: 21.7 DWPD
- Note
- 1. Varies from capacities. The values for performances and power consumptions presented are typical and may vary depending on flash configurations or platform settings. The term idle refers to the standby state of the device.

- Temperature Range
  - Operating:
    - Standard: 0°C to 70°C
    - Wide: -40°C to 85°C
  - Storage: -55°C to 100°C
- Supply Voltage
  - $-5V \pm 5\%$
- Power Consumption<sup>1</sup>
  - Active mode (Max.): 200 mA
  - Idle mode: 85 mA
- Supports Non-Removable Setting
- Supports Toggle 2.0 mode/ONFI 3.0
- OS Support
  - Windows: Win7/8/10 later
  - Mac: 10.2.8/10.8 or later
  - Linux: 2.4.0/2.4.10 or later
- Physical Characteristics
  - Dimensions: 46.85 x 17.20 x 7.70,
    - unit: mm
  - Net weight: 8.5g ± 5%
- LED Indicator for Drive Behavior
- RoHS Recast Compliant
  - Complies with 2011/65/EU Standard

# **Table of Contents**

1. General Description	3
2. Functional Block	3
3. Product Specifications	4
3.1 Capacity	
3.2 Performance	
3.3 Environmental Specifications	5
3.4 Mean Time Between Failures (MTBF)	5
3.5 Certification and Compliance	5
3.6 Endurance	6
3.7 LED Indicator Behavior	6
4. Flash Management	7
4.1 Performance-optimized USB Controller	7
4.2 Power Saving Implemented	7
4.3 Program RAM Architect	7
4.4 Error Correction/Detection (ECC)	7
4.5 Global Wear Leveling	7
4.6 S.M.A.R.T.	8
4.7 Power Failure Management	8
4.8 Bad Block Management	8
4.9 Flash Translation Layer – Page Mapping	8
4.10 SLC-liteX	9
4.11 SMART Read Refresh <sup>TM</sup>	9
5. Electrical Specifications	10
5.1 Absolute Stress Rating	10
5.2 Absolute Maximum Rating	10
5.3 Power Consumption	
6. Mechanical Specifications	12
7. Product Ordering Information	13
7.1 Product Code Designations	
7.2 Valid Combinations	12

## 1. General Description

Apacer UH110-UFD1 is a next-generation USB flash drive compatible with the latest USB specification — USB 3.2 Gen1 SuperSpeed, offering a maximum transfer rate of 5 Gb/s. Compliant with the USB 3.2 specification, this drive delivers outstanding performance of up to 280 MB/s while operating with minimal power consumption. Its compact size and robust metal housing make it perfect for portable flash storage applications.

Utilizing 3D NAND technology for higher capacities up to 64GB and providing greater power efficiency than 2D NAND, UH110-UFD1 is designed to replace conventional IDE hard disk drives. It features an LDPC (Low Density Parity Check) ECC engine and Apacer's SLC-liteX technology, which offers up to 30,000 P/E cycles to extend SSD endurance and increase data reliability. With electrostatic discharge (ESD) prevention in both its mechanical and electronic circuit design, UH110-UFD1 prevents mechanical interference and enhances environmental and ESD protection.

In terms of flash management, UH110-UFD1 incorporates various advanced features, including a powerful hardware ECC engine, wear leveling, S.M.A.R.T., power failure management, flash block management, page mapping, and SMART Read Refresh.

With its exceptional performance, power efficiency, mechanical protection and increased reliability, UH110-UFD1 is an ideal storage solution for a variety of applications, ranging from industrial, imaging, and computing to enterprise markets.

## 2. Functional Block

With embedded firmware, Apacer's UH110-UFD1 contains a controller and flash media with a female connector. It interfaces with the host system allowing data to be written to and read from the flash media.

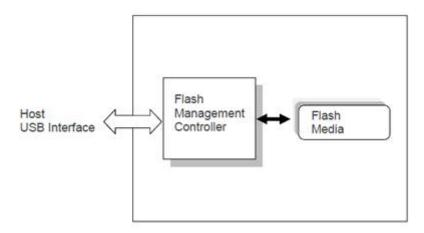


Figure 2-1 Functional Block Diagram

# 3. Product Specifications

## 3.1 Capacity

Capacity specifications of UH110-UFD1 are available as shown in Table 3-1.

**Table 3-1 Capacity Specifications** 

Capacity	apacity Total bytes Total LBA					
32 GB	31,057,674,240	60,659,520				
64 GB	62,032,674,816	121,157,568				

#### Notes:

- Display of total bytes varies from operating systems.
- 1 GB = 1,000,000,000 bytes; 1 sector = 512 bytes.
- LBA count addressed in the table above indicates total user storage capacity and will remain the same throughout the
  lifespan of the device. However, the total usable capacity of the SSD is most likely to be less than the total physical
  capacity because a small portion of the capacity is reserved for device maintenance usages.

#### 3.2 Performance

Performance of UH110-UFD1 is listed below in Table 3-2.

**Table 3-2 Performance Specifications** 

Capacity Performance	32 GB	64 GB
Sequential Read (MB/s)	275	280
Sequential Write (MB/s)	190	190
4K Random Read (IOPS)	3,200	3,200
4K Random Write (IOPS)	1,500	1,500

#### Notes:

- Results may differ from various flash configurations or host system setting, and the above test results are based on the default file structure with FAT 32 file system.
- Sequential read/write is based on CrystalDiskMark 8.0.4 with file size 1,000MB.
- Random read/write is measured using IOMeter with Queue Depth 32.

## 3.3 Environmental Specifications

Environmental specifications of UH110-UFD1 product are shown in Table 3-3.

**Table 3-3 Environmental Specifications** 

Parameter	Туре	Specifications
Tomporatura	Operating	0°C to 70°C (Standard); -40°C to 85°C (Wide)
Temperature	Non-operating	-55°C to 100°C
Vibration Operating  Non-operating		7.69 GRMS, 20~2000 Hz/random (compliant with MIL-STD-810G)
		4.02 GRMS, 15~2000 Hz/random (compliant with MIL-STD-810G)
Shock Operating		Acceleration, 50(G)/11(ms)/half sine (compliant with MIL-STD-202G)
SHOCK	Non-operating	Acceleration, 1500(G)/0.5(ms)/half sine (compliant with MIL-STD-883K)

Note: This Environmental Specification table indicates the conditions for testing the device. Real world usages may affect the results.

## 3.4 Mean Time Between Failures (MTBF)

Mean Time Between Failures (MTBF) is predicted based on reliability data for the individual components in Apacer's USB flash drive. Serving as statistical reference, the prediction result for Apacer's UH110-UFD1 is more than 3,000,000 hours.

Note: The MTBF is predicated and calculated based on "Telcordia Technologies Special Report, SR-332, Issue 3" method.

## 3.5 Certification and Compliance

UH110-UFD1 complies with the following standards:

- CE
- UKCA
- FCC
- RoHS Recast Compliant
- MIL-STD-810G

#### 3.6 Endurance

The endurance of a storage device is predicted by Drive Writes Per Day based on several factors related to usage, such as the amount of data written into the drive, block management conditions, and daily workload for the drive. Thus, key factors, such as Write Amplifications and the number of P/E cycles, can influence the lifespan of the drive.

**Table 3-4 Endurance Specifications** 

Capacity	Drive Writes Per Day
32 GB	21.7
64 GB	21.7

#### Notes:

- This estimation values are based on sequential write behavior.
   (Apacer EDTestTool, test mode –sequential data pattern -100.00% of disk space with 128K)
- Flash vendor guaranteed SLC-liteX P/E cycles: 30K
- WAF may vary from capacity, flash configurations and writing behavior on each platform.
- 1 Terabyte = 1,024GB
- DWPD (Drive Write s Per Day) is calculated based on the number of times that user overwrites the entire capacity of an SSD per day of its lifetime during the warranty period. (SLC liteX warranty: 5 years)

#### 3.7 LED Indicator Behavior

The behavior of the UH110-UFD1 LED indicator is described in Table 3-5.

Table 3-5 LED Behavior

Location	LED Color	Description
As indicated by the red marker below	Blue	LED blinks when the drive is being accessed such as power on, read or write. The blink frequency is 50ms switch H to L and loop



## 4. Flash Management

## 4.1 Performance-optimized USB Controller

The heart of UH110-UFD1 is the USB controller, which translates standard USB signals into the data and controls of the flash media. This proprietary USB controller is specifically designed to attain high data throughput from host to flash.

#### 4.2 Power Saving Implemented

The internal controller of the USB model is designed with power saving implementations, allowing the device to operate at low power consumption.

## 4.3 Program RAM Architect

The internal Program RAM implementation allows the host to upgrade firmware codes anytime when needed.

## 4.4 Error Correction/Detection (ECC)

UH110-UFD1 implements a hardware ECC scheme, based on the Low Density Parity Check (LDPC). LDPC is a class of linear block error correcting code which has apparent coding gain over BCH code because LDPC code includes both hard decoding and soft decoding algorithms. With the error rate decreasing, LDPC can extend SSD endurance and increase data reliability while reading raw data inside a flash chip.

## 4.5 Global Wear Leveling

Flash memory can be erased a limited number of times, This number is called the erase cycle limit, or write endurance limit, The erase cycle limit applies to each individual erase block in the flash device.

In a typical application, and especially if a file system is used, specific pages are constantly updated (e.g., the page that contains the FAT, registry, etc.). Without any special handling, these pages would wear out more rapidly than other pages, reducing the lifetime of the entire flash.

To overcome this inherent deficiency, Apacer's UH110-UFD1 uses Global Wear Leveling algorithm. This algorithm ensures that consecutive writes of a specific sector are not written physically to the same page in the flash. This spreads flash media usage evenly across all pages, thereby maximizing flash lifetime.

The Global Wear Leveling mechanism provides write/erase cycles for reliable data storage over an extended period.

#### 4.6 S.M.A.R.T.

S.M.A.R.T. is an abbreviation for Self-Monitoring, Analysis and Reporting Technology, a self-monitoring system that provides indicators of drive health as well as potential disk problems. It serves as a warning for users from unscheduled downtime by monitoring and displaying critical drive information. Ideally, this should allow taking proactive actions to prevent drive failure and make use of S.M.A.R.T. information for future product development reference.

ID (Hex)
Attribute Name

162 (0xA2)
Spare Block Count

163 (0xA3)
Maximum Erase Count

164 (0xA4)
Average Erase Count

166 (0xA6)
Total Later Bad Block Count

167 (0xA7)
Protect Mode

**Table 4-1 SMART Attribute ID List** 

## 4.7 Power Failure Management

Power Failure Management plays a crucial role when power supply becomes unstable. Power disruption may occur when users are storing data into the SSD, leading to instability in the drive. However, with Power Failure Management, a firmware protection mechanism will be activated to scan pages and blocks once power is resumed. Valid data will be transferred to new blocks for merging and the mapping table will be rebuilt. Therefore, data reliability can be reinforced, preventing damage to data stored in the NAND Flash.

## 4.8 Bad Block Management

Current production technology is unable to guarantee total reliability of NAND flash memory array. When a flash memory device leaves factory, it comes with a minimal number of initial bad blocks during production or out-of-factory as there is no currently known technology that produce flash chips free of bad blocks. In addition, bad blocks may develop during program/erase cycles. Since bad blocks are inevitable, the solution is to keep them in control. Apacer flash devices are programmed with ECC, page mapping technique and S.M.A.R.T to reduce invalidity or error. Once bad blocks are detected, data in those blocks will be transferred to free blocks and error will be corrected by designated algorithms.

## 4.9 Flash Translation Layer – Page Mapping

Page mapping is an advanced flash management technology whose essence lies in the ability to gather data, distribute the data into flash pages automatically, and then schedule the data to be evenly written. Page-level mapping uses one page as the unit of mapping. The most important characteristic is that each logical page can be mapped to any physical page on the flash memory device. This mapping algorithm allows different sizes of data to be written to a block as if the data is written to a data pool and it does not need to take extra operations to process a write command. Thus, page mapping is adopted to increase random access speed and improve SSD lifespan, reduce block erase frequency, and achieve optimized performance and lifespan.

# Apacer

#### 4.10 SLC-liteX

SLC-liteX is based on 3D NAND technology. The firmware is carefully tweaked by our engineering team so as to offer the greatest number of P/E cycles in this format – 30,000, which is 10 times more than MLC or industrial 3D TLC. The longest lifespans are therefore available at reasonable cost.

#### 4.11 SMART Read Refresh™

Apacer's SMART Read Refresh plays a proactive role in avoiding read disturb errors from occurring to ensure health status of all blocks of NAND flash. Developed for read-intensive applications in particular, SMART Read Refresh is employed to make sure that during read operations, when the read operation threshold is reached, the data is refreshed by re-writing it to a different block for subsequent use.

# 5. Electrical Specifications

## **5.1 Absolute Stress Rating**

Table 5-1 lists the absolute stress rating for UH110-UFD1.

**Caution: Absolute Maximum Stress Ratings –** Applied conditions greater than those listed under "Absolute Maximum Stress Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these conditions or conditions greater than those defined in the operational sections of this data sheet is not implied. Exposure to absolute maximum stress rating conditions may affect device reliability.

**Table 5-1 Absolute Stress Rating** 

Item	Range
Required power supply	5V ± 5% (4.75-5.25V)

## 5.2 Absolute Maximum Rating

Table 5-2 lists the absolute maximum power ratings for UH110-UFD1.

**Table 5-2 Absolute Maximum Power Ratings** 

Parameter	Min	Тур	Max	Unit
Operating Temperature (Commercial)	0	+25	+70	°C
Storage Temperature (Commercial)	-25	+25	+85	°C
Operating Temperature (Industrial)	-40	+25	+85	°C
Storage Temperature (Industrial)	-50	+25	+125	°C
1.1V Regulator Power Supply	1.04	1.12	1.20	V
1.8V Regulator Power Supply	1.76	1.86	2.0	V
3.3V Regulator Power Supply	3.15	3.3	3.45	V
5.0V Regulator Power Supply	3.0	5.0	5.5	V
2.5V Regulator Power Supply	2.35	2.5	2.7	V
1.2V Regulator Power Supply	1.13	1.2	1.3	V

# **5.3 Power Consumption**

Table 5-3 lists the power consumption for UH110-UFD1.

**Table 5-3 Power Consumption** 

Capacity	Unit	32 GB	64 GB
Active (Max.)	mΛ	190	200
Idle	mA	85	85

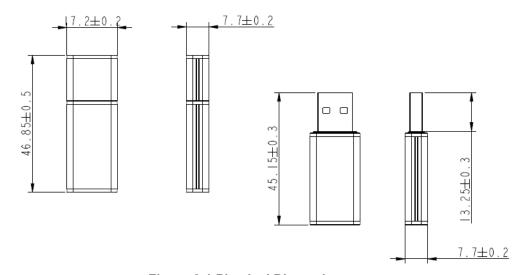
#### Notes:

- All values are typical and may vary depending on flash configurations or host system settings. Power consumption is measured using CrystalDiskMark 8.0.4 with file size 1,000MB.

# **6. Mechanical Specifications**

**Table 6-1 Physical Information** 

Parameter	Unit	32 GB 64 GB						
Length		46.85 ± 0.50						
Width	mm	17.20	$0 \pm 0.20$					
Height		7.70 :	0.20					
Weight	g ± 5%	8.5						



**Figure 6-1 Physical Dimensions** 

# 7. Product Ordering Information

## 7.1 Product Code Designations

Apacer's UH110-UFD1 USB is available in different configurations and densities. See the chart below for a comprehensive list of options for the UH110-UFD1 series devices.

Code	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
Code	Α	Ν	2		1	1	8	Χ	Χ	G		Χ	Χ	Χ	3	3

Code 1-3 (Product Line & Form Factor)	USB+UFD1
Code 5-6 (Model/Solution)	UH110-UFD1
Code 7-8 (Product Capacity)	8H: 32GB (SLC-liteX) 8J: 64GB (SLC-liteX)
Code 9 (Flash Type & Product Temp)	L: 3D SLC-liteX Standard Temperature M: 3D SLC-liteX Wide Temperature
Code 10 (Product Spec)	UH110-UFD1 sliver-gray housing
Code 12-14 (Version Number)	Random numbers generated by system
Code 15-16 (Firmware Version)	UFPA4AEA

#### 7.2 Valid Combinations

The following table lists the available models of the UH110-UFD1 series which are in mass production or will be in mass production. Consult your Apacer sales representative to confirm availability of valid combinations and to determine availability of new combinations.

Capacity	Standard Temperature	Wide Temperature
32GB	AN2.118HLG.00333	AN2.118HMG.00333
64GB	AN2.118JLG.00333	AN2.118JMG.00233

# Apacer

# **Revision History**

Revision	Description	Date
1.0	Initial release	8/12/2022
1.1	Added Table 4-1 to 4.6 S.M.A.R.T.	11/4/2022
1.2	Modified non-operating vibration specification at Table 3-3 by changing sine to random     Added UKCA to 3.5 Certification and Compliance	12/26/2022
1.3	Updated Performance and Power Consumption on Specifications     Overview page, Table 3-2 and 5-3     Updated 7. Product Ordering Information due to firmware change	8/6/2024

## **Global Presence**

#### Taiwan (Headquarters)

Apacer Technology Inc.

1F., No.32, Zhongcheng Rd., Tucheng Dist., New Taipei City 236, Taiwan R.O.C.

Tel: 886-2-2267-8000 Fax: 886-2-2267-2261 amtsales@apacer.com

#### Japan

**Apacer Technology Corp.** 

6F, Daiyontamachi Bldg., 2-17-12, Shibaura, Minato-Ku, Tokyo, 108-0023, Japan

Tel: 81-3-5419-2668 Fax: 81-3-5419-0018 jpservices@apacer.com

#### China

Apacer Electronic (Shanghai) Co., Ltd

Room D, 22/FL, No.2, Lane 600, JieyunPlaza, Tianshan RD, Shanghai, 200051, China

Tel: 86-21-6228-9939 Fax: 86-21-6228-9936 sales@apacer.com.cn

#### U.S.A.

Apacer Memory America, Inc.

46732 Lakeview Blvd., Fremont, CA 94538

Tel: 1-408-518-8699 Fax: 1-510-249-9551 sa@apacerus.com

#### Europe

Apacer Technology B.V.

Science Park Eindhoven 5051 5692 EB Son, The Netherlands

Tel: 31-40-267-0000 Fax: 31-40-290-0686 sales@apacer.nl

#### India

Apacer Technologies Pvt Ltd,

1874, South End C Cross, 9<sup>th</sup> Block Jayanagar, Bangalore-560069, India

Tel: 91-80-4152-9061/62 Fax: 91-80-4170-0215 sales\_india@apacer.com